

Search Notes

Application/Control No.

10/630,223

Examiner

S. Devi, Ph.D.

Applicant(s)/Patent under
Reexamination

MICHON ET AL.

Art Unit

1645

SEARCHED

Class	Subclass	Date	Examiner
424	194.1 193.1 244.1 831 234.1 184.1	10/19/2006	SD
536	123.1	10/19/2006	SD
514	23	10/19/2006	SD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BITECH-STIC: Text search Inventors' name search See SCORE on IFW for search reports. Search strategy enclosed	9/20/2006	SD
PALM: Priority Inventors - ODP	10/19/2006	SD